

Pa - IDC

QUERY CONTROL FORM

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Application No.	<u>09/839,981</u>	Prepared by	<u>JML</u>	Tracking Number	<u>05933838</u>
Examiner-GAU	<u>Sircus - 283G</u>	Date	<u>5/14/04</u>	Week Date	<u>4/12/04</u>
		No. of queries	<u>(1)</u>		<u>IFW</u>

JACKET

- | | | | |
|----------------------|------------------------|--------------------|----------------|
| a. Serial No. | f. Foreign Priority | k. Print Claim(s) | p. PTO-1449 |
| b. Applicant(s) | g. Disclaimer | l. Print Fig. | q. PTOL-85b |
| c. Continuing Data | h. Microfiche Appendix | m. Searched Column | r. Abstract |
| d. PCT | i. Title | n. PTO-270/328 | s. Sheets/Figs |
| e. Domestic Priority | j. Claims Allowed | o. PTO-892 | t. Other |

SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

MESSAGE

*PTO - 1449 : "Please either initial or line
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Thank you

CLAIMS

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initials JML

RESPONSE

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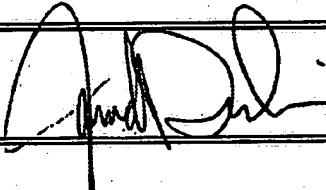
OTHER DOCUMENTS
(Including Author, Title, Date, Pertinent Pages, Etc.)

"Dynamic Safe-Area Protection for Power Transistors Employs Peak-Temperature Limiting" by Robert J. Widlar and Mineo Yamatake, IEEE Journal of Solid-State Circuits, Vol. SC-22, No. 1, February 1987, pp. 77-84

"A 15-W Monolithic Power Operational Amplifier" by Paul R. Gray, IEEE Journal of Solid-State Circuits, Vol. SC-7, No. 6, December 1972, pp. 474-480

"High-Gain 15-W Monolithic Power Amplifier With Internal Fault Protection" by Ernest L. Long and Thomas M. Frederiksen, IEEE Journal of Solid-State Circuits, Vol. SC-6, No. 1, February 1971, pp. 35-44

"Power Integrated Circuits: Problems, Tradeoffs, and Solutions" by Bruno Murari, IEEE Journal of Solid-State Circuits, Vol. SC-13, No. 3, June 1978, pp. 307-319

Examiner	Date Considered
	6/17/03